

Description

The AP15N10D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.



 $V_{DS} = 100V I_{D} = 19.3A$

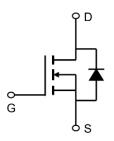
 $R_{DS(ON)}$ < $85m\Omega$ @ V_{GS} =10V (Type: $65m\Omega$)

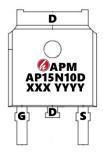


Lithium battery protection

Wireless impact

Mobile phone fast charging







Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP15N10D	TO-252-3L	AP15N10D XXX YYYY	2500

Absolute Maximum Ratings (TC=25 ℃unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	100	V
VGS	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Drain Current, V _{GS} @ 10V	19.3	А
I _D @T _C =100℃	Drain Current, V _{GS} @ 10V	10	Α
IDM	Pulsed Drain Current ¹	57.9	Α
P _D @T _C =25℃	Total Power Dissipation	30	W
P _D @T _A =25°C	Total Power Dissipation ³	2.7	W
EAS	Single Pulse Avalanche Energy ⁴	7	mJ
TSTG	Storage Temperature Range	-55 to 150	$^{\circ}\!\mathbb{C}$
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}\!\mathbb{C}$
RθJA	Maximum Thermal Resistance, Junctionambient	55	°C/W
RθJC	Maximum Thermal Resistance, Junction-case	5.1	°CW



Electrical Characteristics@Tj=25°C(unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	Source Breakdown Voltage VGS=0V, ID=250µA		107	-	V
IDSS	Zero Gate Voltage Drain Current	VDS=100V, VGS=0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	VDS=0V, VGS=±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250μA	1.2	1.85	2.5	V
DDC(-r-)	Ctatic Dunin Course on Desistance water	VGS=10V, ID=5A	-	65	85	mΩ
RDS(on)	Static Drain-Source on-Resistance note3	VGS=4.5V, ID=3A	-	75	100	mΩ
g fs	Forward Transconductance	V DS =5V , I D =5A		14		S
RG	Gate Resistance	VDS = 0V, VGS =0V,f =1MHz		3		Ω
Ciss	Input Capacitance		-	1100	-	pF
Coss	Output Capacitance	VDS=15V, VGS=0V, f=1.0MHz	-	55	-	pF
Crss	Reverse Transfer Capacitance			40	-	pF
Qg	Total Gate Charge	VDS=50V.		11.9	-	nC
Qgs	Gate-Source Charge	ID=5A,	-	2.8	-	nC
Qgd	Gate-Drain("Miller") Charge	VGS=10V		1.7	-	nC
td(on)	Turn-on Delay Time		-	3.8	-	ns
tr	Turn-on Rise Time	VDS=30V, ID=5A,	-	25.8	-	ns
td(off)	Turn-off Delay Time	RG=1.8Ω, VGS=10V	-	16	-	ns
tf	Turn-off Fall Time		-	8.8	-	ns
IS	Continuous Source Current1,5	VG=VD=0V , Force Current	-	1	14.6	Α
ISM	Pulsed Source Current2,5	VO-VD-0V, I GIGG Guillent	-	1	25	Α
VSD	Diode Forward Voltage2	VGS=0V, IS=10A	-	-	1.2	V

Notes:

- 1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- $2\sqrt{100}$ The data tested by pulsed , pulse width ≤ 300 us , duty cycle $\leq 2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD =80V,VGS =10V,L=0.1mH,I AS =7A
- 4. The power dissipation is limited by 150 ℃ junction temperature
- 5. The data is theoretically the same as I D and I DM, in real applications, should be limited by total power dissipation



Typical Characteristics

100V N-Channel Enhancement Mode MOSFET

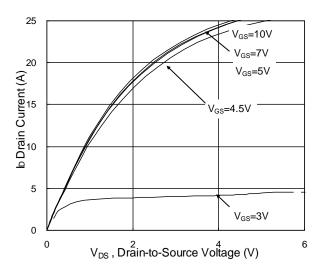


Fig.1 Typical Output Characteristics

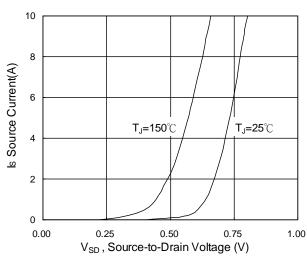


Fig.3 Forward Characteristics Of Reverse

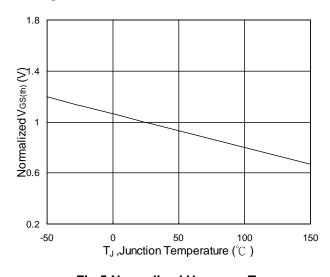


Fig.5 Normalized $V_{\text{GS(th)}}$ vs. T_J

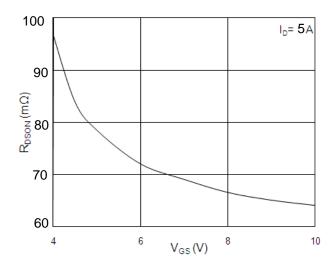


Fig.2 On-Resistance vs. Gate-Source

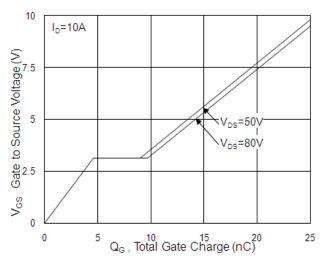


Fig.4 Gate-Charge Characteristics

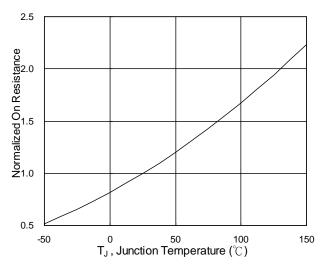
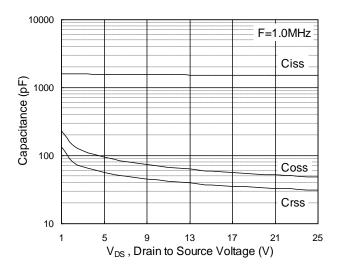


Fig.6 Normalized R_{DSON} vs. T_J







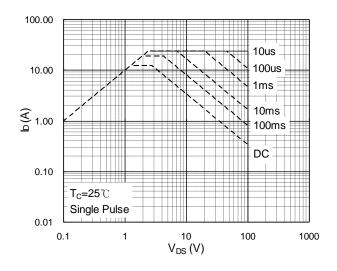


Fig.7 Capacitance

Fig.8 Safe Operating Area

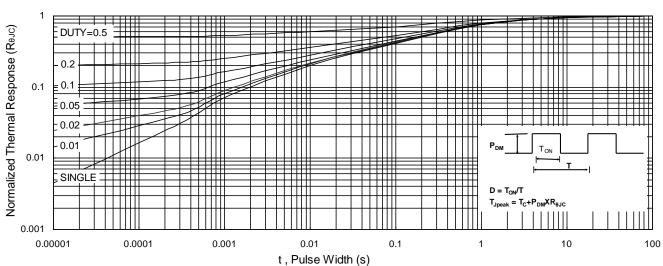
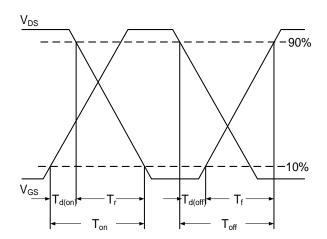
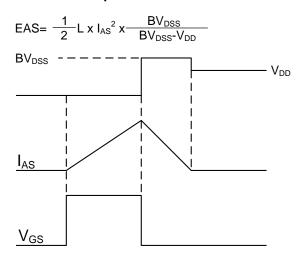


Fig.9 Normalized Maximum Transient Thermal Impedance



10 Switching Time Waveform

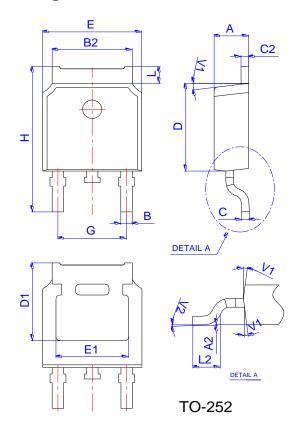


11 Unclamped Inductive Switching Waveform



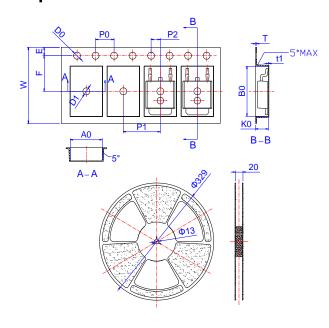


Package Mechanical Data



	Dimensions					
Ref.		Millimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583





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Edition	Date	Change
Rve3.0	2018/1/31	Initial release
Rve3.1	2021/1/3	Reduce RDS(on)

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